

**IN THE ABSTRACT OF THE DISCLOSURE**

Please amend the Abstract as follows:

**Abstract of the Disclosure**

A method of ~~leakage test for~~ testing an integrated circuit includes applying a voltage to one of the pins of the integrated circuit. The pin is floated for a predetermined time. A measurement is performed after the predetermined time. The measurement involves by sampling the RC time constant of leakage current of the pins of the integrated circuit.